## Search Notes



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Applicant(s)/Patent Under Reexamination

NIHEI ET AL.

Examiner

Art Unit

Mack, Chanelle N

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## **SEARCHED**

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Class	Subclass	Date	Examiner		
345	84-85, 107	02/19/2008	C. Mack		
359	296	02/19/2008	C. Mack		

## **SEARCH NOTES**

Search Notes	Date	Examiner

## **INTERFERENCE SEARCH**

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